## Notice of References Cited Application/Control No. 10/809,841 Examiner Phillip Nguyen Applicant(s)/Patent Under Reexamination FUTAMI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,529,463	03-2003	Goodberlet, James G.	369/109.02
*	В	US-6,243,348	06-2001	Goodberlet, James G.	369/101
*	O	US-5,363,221	11-1994	Sutton et al.	359/11
*	D	US-2002/0097790	07-2002	Dress et al.	375/219
*	E	US-6,621,878	09-2003	Dress et al.	375/316
*	F	US-2003/0039036 A1	02-2003	Kruschwitz et al.	359/707
*	G	US-2003/0035187 A1	02-2003	Richardson et al.	359/189
*	Н	US-2006/0204170 A1	09-2006	Igarashi et al.	385/024
*	-	US-2006/0251134 A1	11-2006	Volodin et al.	372/022
*	J	US-2004/0109695	06-2004	Watanabe, Shigeki	398/186
	К	US-		·	
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country .	Name .	Classification
	· N					
	0					
	Р					
	α					
	R					
	S					·
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.